Compact ESD Tester

HCE-5000

Stand-alone ESD test system

The Hanwa Compact ESD Tester has been designed for portability, improved use of space and high cost performance.
Perform HBM, MM and leakage measurement without a PC or curve tracer.

Zap unit

Features

Easy-to-use touch screen interface

Settings can be adjusted without a PC.

Complies with a wide variety of standards

Satisfies JEDEC/ESDA/AEC/ JEITA for HBM/MM

Leakage & Curve tracing

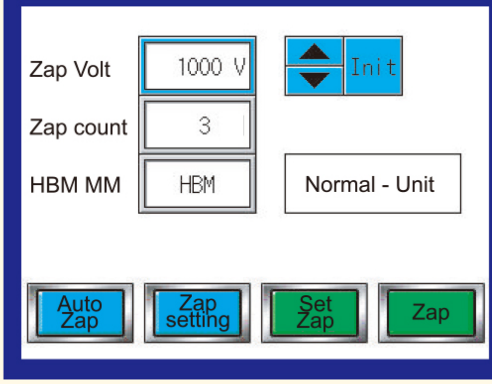
Before and after testing.
Method 1: Percentage of change
Method 2: Absolute value

HBM Fast/Slow Unit (Optional)

Two types of units for variations in HBM waveform rise time.
Fast rise time = 2-3ns, Slow rise time = 8-10ns (std = 5-7ns)

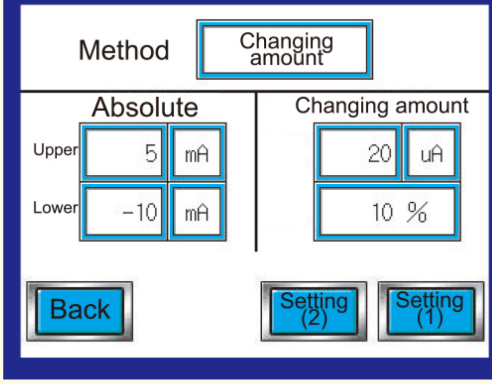
Panel view

Zap screen


Zap Volt: 1000 V
Zap count: 3
HBM MM: HBM
Normal - Unit

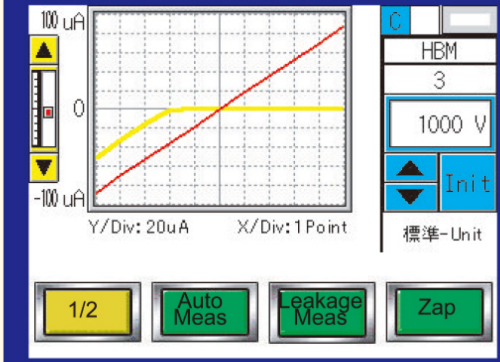
This is Manual Zap menu

Judgment criteria Specifications


Method: Changing amount
Absolute
Upper: 5 mA
Lower: -10 mA
Changing amount
20 uA
10 %

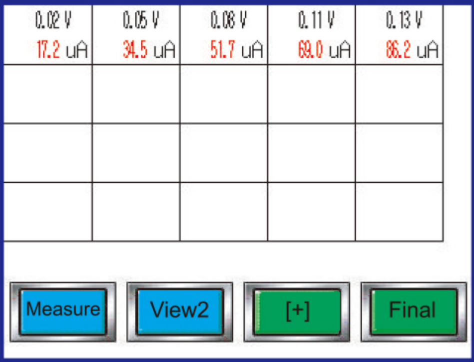
This is Judge setting menu

Result screen



HBM
3
1000 V
標準-Unit

< Graph view >



0.02 V	0.05 V	0.08 V	0.11 V	0.13 V
17.2 uA	34.5 uA	51.7 uA	69.0 uA	86.2 uA

< Table view >

The result has graph & table

Specification

Model	HCE-5000
Charge Voltage	10V to 4kV step 5V
Charge Voltage	1%+/-10V
Zap polarity	+/-
Zap count	1 to 99
Zap interval	0.1s to 9.9s / Step 0.1s
Standard zap unit	HBM=4kV, MM=4kV
Standards	JEDEC/ESDA/AEC/JEITA
Leakage voltage	+/-40V / Step 0.1V
Leakage voltage accuracy	1%+/-50mV
Leakage current	MAX 100mA
Measurement current accuracy	High:1%+/-1/500FS+/-10nA Low:2%+/-1/500FS+/-100nA (Range of RL/RD<=1000)
Measure point	Max 20 points
Leak detection resistance	10/100/1k/10k/100k/1M (ohm)

AC power	AC100V 2A 50/60 Hz
Dimensions	350(W)×208(D)×296(H) mm
Weight	10kg
Interface	RS-232C
Temperature	15 to 35˚C
Humidity	0 to 70% (non-condensing)

Accessories

美浜国际贸易（上海）有限公司

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● Agency

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